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Author index

Agosteo, S., C. Birattari, A.F. Para, L. Gini, A. Mitaroff, M. Silari and L. Ulrici, Neutron production from 158 GeV/c per nucleon lead ions on thin copper and lead targets in the angular range 30–135° 194 (2002) 399
Alegaonkar, P.S., A.B. Mandale, S.R. Sainkar and V.N. Bhoraskar, Refractive index and dielectric constant of the boron and fluorine diffused polyimide 194 (2002) 281
An, Z. and M.T. Liu, On the efficiency calibration of Si(Li) detector in the low-energy region using thick-target bremsstrahlung 194 (2002) 513
Andersen, H.H., A. Csete, T. Ichioka, H. Knudsen, S.P. Møller and U.I. Uggerhøj, An apparatus to measure stopping powers for low-energy antiprotons and protons 194 (2002) 217
Andrianov, M.V., see Jbara, O. 194 (2002) 302
Andrighetto, A., see Radivojevic, Z. 194 (2002) 251
Asai, K., see Shibuya, K. 194 (2002) 207
Avasthi, D.K., see Sharma, A. 194 (2002) 7

Baba, Y., T. Sekiguchi and I. Shimoyama, Local electronic and geometric structures of silicon atoms implanted in graphite 194 (2002) 41
Bajeat, O., see Roussière, B. 194 (2002) 151
Barradas, N.P., C. Jeynes, R.P. Webb and E. Wendler, Accurate determination of the stopping power of ^{4}He in Si using Bayesian inference 194 (2002) 15
Barré, N., see Roussière, B. 194 (2002) 151
Barzakh, A.E., see Portillo, M. 194 (2002) 193
Baving, P., H.W. Becker, C. Rolfs and H. Zabel, Stopping power of He ions in niobium from a comparison of RBS and X-ray reflectivity measurements 194 (2002) 363
Becker, H.W., see Baving, P. 194 (2002) 363
Belhaj, M., see Jbara, O. 194 (2002) 302
Belmont-Moreno, E., see Cruz-Galindo, H.S. 194 (2002) 319
Belyakov, V.S., see Titov, A.I. 194 (2002) 323
Berdejo, H.M., see Romero, S. 194 (2002) 164
Beznosjuk, V.I., see Portillo, M. 194 (2002) 193
Bhoraskar, S.V., see Naddaf, M. 194 (2002) 54
Bhoraskar, V.N., see Alegaonkar, P.S. 194 (2002) 281
Biino, C., M. Clément, N. Doble, K. Elsener, A. Freund, L. Gatignon, P. Grafström, W. Herr, A. Taratin, U.I. Uggerhøj, V.V. Uzhinskii and M. Velasco, On the reduced interaction probability for fully stripped 33 TeV/c Pb ions channeled in a bent Si crystal 194 (2002) 417
Birattari, C., see Agosteo, S. 194 (2002) 399
Bouffard, S., see Costantini, J.-M. 194 (2002) 132
Bourgeois, M., see Javorsek II, D. 194 (2002) 78
Brabec, V., see Dragoun, O. 194 (2002) 112
Brandolini, F., see Radivojevic, Z. 194 (2002) 251
Brongersma, H.H., see Reijme, M.A. 194 (2002) 346
Brusa, R.S., W. Deng, G.P. Karwasz and A. Zecca, Doppler-broadening measurements of positron annihilation with high-momentum electrons in pure elements 194 (2002) 519

Cazaux, J., see Jbara, O. 194 (2002) 302
Chakane, S., see Naddaf, M. 194 (2002) 54

PII: S0168-583X(02)01448-9

Chandorkar, A.N., see Vaidya, S.J. 194 (2002) 311
Chang, C.-L. and D.-Y. Wang, Characterization of surface enhancement of carbon ion-implanted TiN coatings by metal vapor vacuum arc ion implantation 194 (2002) 463
Chen, C.C., A.-C. Lindgren, S.L. Zhang and D.Z. Zhu, Retardation of strain relaxation in Si/SiGe/Si heterostructures during high temperature oxidation 194 (2002) 474
Chen, C., X.-L. Wang, Q.-M. Lu, G. Fu, S.-L. Li, F. Lu, K.-M. Wang and D.-Y. Shen, Property study on nickel ion implanted planar waveguide in $KTiOAsO_4$ crystal 194 (2002) 355
Chen, J.L., see Xu, J.L. 194 (2002) 297
Clapier, F., see Roussière, B. 194 (2002) 151
Clément, M., see Biino, C. 194 (2002) 417
Coban, A., E.E. Khawaja and S.M.A. Durrani, Difference between bulk and thin film densities of metal oxide and fluoride films studied by NRA depth profiling techniques 194 (2002) 171
Costantini, J.-M., F. Couvreur, J.-P. Salvetat and S. Bouffard, Micro-Raman study of the carbonization of polyimide induced by swift heavy ion irradiations 194 (2002) 132
Cottereau, E., see Roussière, B. 194 (2002) 151
Couvreur, F., see Costantini, J.-M. 194 (2002) 132
Cruz-Galindo, H.S., K. Michaelian, A. Martínez-Dávalos, E. Belmont-Moreno and S. Galindo, Luminescence model with quantum impact parameter for low energy ions 194 (2002) 319
Csete, A., see Andersen, H.H. 194 (2002) 217
Cucinotta, F.A., see Tripathi, R.K. 194 (2002) 229

de Hosson, J.Th.M., see Holgado, J.P. 194 (2002) 333
de Jong, M.P., see Reijme, M.A. 194 (2002) 346
de Voigt, M.J.A., see Reijme, M.A. 194 (2002) 346
de Voigt, M.J.A., see Selen, L.J.M. 194 (2002) 479
Dendooven, P., see Radivojevic, Z. 194 (2002) 251
Denier van der Gon, A.W., see Reijme, M.A. 194 (2002) 346
Deng, W., see Brusa, R.S. 194 (2002) 519
Diao, L., see He, M. 194 (2002) 393
Ditrói, F., see Ido, T. 194 (2002) 369
Diwan, P.K., see Sharma, A. 194 (2002) 7
Doble, N., see Biino, C. 194 (2002) 417
Dong, C., see Li, X.-n. 194 (2002) 47
Donzaud, C., see Roussière, B. 194 (2002) 151
Dragoun, O., A. Špalek, A. Kovalík, E.A. Yakushev, M. Ryšavý, J. Frána, V. Brabec, A.F. Novgorodov and D. Liljequist, Scattering of 7.3 keV conversion electrons from a ^{57}Co source covered gradually by gold absorbers of various thicknesses 194 (2002) 112
Ducourtieux, M., see Roussière, B. 194 (2002) 151
Dunne, J.A., Monte Carlo simulations of neutron fluxes for varying rock types 194 (2002) 226
Durrani, S.M.A., see Coban, A. 194 (2002) 171

Elmore, D., see Javorsek II, D. 194 (2002) 78
Elsener, K., see Biino, C. 194 (2002) 417
Endo, S., E. Yoshida, H. Nikjoo, S. Uehara, M. Hoshi, M. Ishikawa and K. Shizuma, A Monte Carlo track structure code for low energy protons 194 (2002) 123
Essabaa, S., see Roussière, B. 194 (2002) 151

Fakhfakh, S., see Jbara, O. 194 (2002) 302
Fasasi, M.K., see Obiajunwa, E.I. 194 (2002) 61
Fedorov, D.V., see Portillo, M. 194 (2002) 193
Feng, J.Y., see Liu, J.F. 194 (2002) 289
Feng, J.Y., see Xu, J.L. 194 (2002) 297
Fernández, M., see Romero, S. 194 (2002) 164
Filippov, M., see Jbara, O. 194 (2002) 302
Fischbach, E., see Javorsek II, D. 194 (2002) 78
Foglio Para, A., see Agosteo, S. 194 (2002) 399
Frána, J., see Dragoun, O. 194 (2002) 112

Freund, A., see Biino, C. 194 (2002) 417
Fu, G., see Chen, F. 194 (2002) 355

Galindo, R.E., see Holgado, J.P. 194 (2002) 333
Galindo, S., see Cruz-Galindo, H.S. 194 (2002) 319
Gatignon, L., see Biino, C. 194 (2002) 417
Ghosh, S., see Sharma, A. 194 (2002) 7
Gillen, D.R., W.G. Graham and A. Goelich, Sputtering of copper atoms by keV atomic and molecular ions: A comparison of experiment with analytical and computer based models 194 (2002) 409
Gini, L., see Agosteo, S. 194 (2002) 399
Goelich, A., see Gillen, D.R. 194 (2002) 409
Gomes, I., see Portillo, M. 194 (2002) 193
González-Elipe, A.R., see Holgado, J.P. 194 (2002) 333
Grafström, P., see Biino, C. 194 (2002) 417
Graham, W.G., see Gillen, D.R. 194 (2002) 409
Grigorjeva, L., see Millers, D. 194 (2002) 469
Gröbner, O., see Le Pimpec, F. 194 (2002) 434
Guillemaud-Mueller, D., see Roussière, B. 194 (2002) 151

Hanamoto, K., see Kimura, Y. 194 (2002) 187
Hatori, S., see Ishigami, R. 194 (2002) 257
He, M., S. Jiang, S. Jiang, L. Diao, S. Wu and C. Li, Measurement of the half-life of ^{79}Se with PX-AMS . . . 194 (2002) 393
Hermanne, A., see Ido, T. 194 (2002) 369
Herr, W., see Biino, C. 194 (2002) 417
Hillegonds, D., see Javorsek II, D. 194 (2002) 78
Holgado, J.P., R.E. Galindo, A. van Veen, H. Schut, J.Th.M. de Hosson and A.R. González-Elipe, Structural effects due to the incorporation of Ar atoms in the lattice of ZrO_2 thin films prepared by ion beam assisted deposition 194 (2002) 333
Hoshi, M., see Endo, S. 194 (2002) 123
Hughes, E.W., see Mastromarino, P.A. 194 (2002) 69

Ibrahim, F., see Roussière, B. 194 (2002) 151
Ichioka, T., see Andersen, H.H. 194 (2002) 217
Ido, T., A. Hermanne, F. Ditrói, Z. Szűcs, I. Mahunka and F. Tárkányi, Excitation functions of proton induced nuclear reactions on ^{nat}Rb from 30 to 70 MeV. Implication for the production of ^{82}Sr and other medically important Rb and Sr radioisotopes 194 (2002) 369
Ishigame, M., see Matsunami, N. 194 (2002) 443
Ishigami, R., Y. Ito, K. Yasuda, M. Sasase and S. Hatori, Transmission ERDA measurement of deuterium in titanium with thickness ~70 μm using 15 MeV ^{4}He beams 194 (2002) 257
Ishikawa, M., see Endo, S. 194 (2002) 123
Ito, Y., see Ishigami, R. 194 (2002) 257
Iwahara, H., see Matsunami, N. 194 (2002) 443

Jain, S., see Naddaf, M. 194 (2002) 54
Javorsek II, D., D. Elmore, E. Fischbach, T. Miller, M. Stohler, M. Bourgeois, D. Hillegonds, J. Marder, H. Rohrs and S. Vogt, Testing the atomic structure of beryllium with AMS 194 (2002) 78
Jayavel, P., see Santhakumar, K. 194 (2002) 451
Jbara, O., S. Fakhfakh, M. Belhaj, J. Cazaux, E.I. Rau, M. Filippov and M.V. Andrianov, A new experimental approach for characterizing the internal trapped charge and electric field build up in ground-coated insulators during their e^- irradiation 194 (2002) 302
Jeynes, C., see Barradas, N.P. 194 (2002) 15
Jiang, S., see He, M. 194 (2002) 393
Jiang, S., see He, M 194 (2002) 393
Johnson-Fatokun, F.O., see Obiajunwa, E.I. 194 (2002) 61
Johnson-Fatokun, F.O., see Obiajunwa, E.I. 194 (2002) 65

Kaito, C., see Kimura, Y. . . . 194 (2002) 187
Kapphan, S.E., see Millers, D. . . . 194 (2002) 469
Karolewski, M.A., Classical dynamics simulations of directional effects in sputtering from a bimetallic surface: c(2 × 2)-Pb/Cu(1 0 0) . . . 194 (2002) 26
Karwasz, G.P., see Brusa, R.S. . . . 194 (2002) 519
Kesavamoorthy, R., see Santhakumar, K. . . . 194 (2002) 451
Khanna, A., see Singh, K. . . . 194 (2002) 1
Khawaja, E.E., see Coban, A. . . . 194 (2002) 171
Kimura, Y., K. Hanamoto, Y. Nakayama and C. Kaito, Irradiation effect of synchrotron radiation on crystallization of thin amorphous WO_3 film . . . 194 (2002) 187
Knudsen, H., see Andersen, H.H. . . . 194 (2002) 217
Koshimizu, M., see Shibuya, K. . . . 194 (2002) 207
Kovalík, A., see Dragoun, O. . . . 194 (2002) 112
Kucheyev, S.O., see Titov, A.I. . . . 194 (2002) 323
Kumar, A., J.S. Shahi, S. Puri, D. Mehta and N. Singh, Differential cross-section measurements for inelastic scattering of 22.1 keV photons by elements with $4 \leqslant Z \leqslant 69$ . . . 194 (2002) 99
Kumar, A., J.S. Shahi, D. Mehta and N. Singh, Differential cross-section measurements for elastic scattering of 22.1 keV photons by elements with $6 \leqslant Z \leqslant 81$ . . . 194 (2002) 105
Kumar, R., see Singh, K. . . . 194 (2002) 1
Kumar, S., see Sharma, A. . . . 194 (2002) 7

Lau, C., see Roussière, B. . . . 194 (2002) 151
Laurent, J.M., see Le Pimpec, F. . . . 194 (2002) 434
Le Blanc, F., see Roussière, B. . . . 194 (2002) 151
Le Pimpec, F., O. Gröbner and J.M. Laurent, Electron stimulated molecular desorption of a non-evaporable Zr–V–Fe alloy getter at room temperature . . . 194 (2002) 434
Lefort, H., see Roussière, B. . . . 194 (2002) 151
Li, S.-L., see Chen, F. . . . 194 (2002) 355
Li, C., see He, M. . . . 194 (2002) 393
Li, X.-n., D. Nie and C. Dong, A comparative study on microstructures of β-$FeSi_2$ and carbon-doped β-$Fe(Si,C)_2$ films by transmission electron microscopy . . . 194 (2002) 47
Li, W.Z., see Liu, J.F. . . . 194 (2002) 289
Liang, C.F., see Roussière, B. . . . 194 (2002) 151
Liljequist, D., see Dragoun, O. . . . 194 (2002) 112
Lindgren, A.-C., see Chen, C.C. . . . 194 (2002) 474
Liu, J.F., J.Y. Feng and W.Z. Li, Reduction of the tensile stress in $CoSi_2$ films by pre-deposition carbon ion implantation . . . 194 (2002) 289
Liu, M.T., see An, Z. . . . 194 (2002) 513
Lu, F., see Chen, F. . . . 194 (2002) 355
Lu, Q.-M., see Chen, F. . . . 194 (2002) 355
Lyapin, V., see Radivojevic, Z. . . . 194 (2002) 251

Magudapathy, P., see Santhakumar, K. . . . 194 (2002) 451
Mahunka, I., see Ido, T. . . . 194 (2002) 369
Mandale, A.B., see Naddaf, M. . . . 194 (2002) 54
Mandale, A.B., see Alegaonkar, P.S. . . . 194 (2002) 281
Marder, J., see Javorsek II, D. . . . 194 (2002) 78
Martínez-Dávalos, A., see Cruz-Galindo, H.S. . . . 194 (2002) 319
Mastromarino, P.A., C.R. Otey, D. Pripstein and E.W. Hughes, Tunable diode laser study of pressure broadening of Rb D_1 lines in the presence of ^4He buffer gas . . . 194 (2002) 69
Matsunami, N., T. Shimura, H. Iwahara, N. Sata and M. Ishigame, Ion irradiation effects on $SrCeO_3$ thin films . . . 194 (2002) 443
Mayer, M., Ion beam analysis of rough thin films . . . 194 (2002) 177
Mehta, D., see Kumar, A. . . . 194 (2002) 99
Mehta, D., see Kumar, A. . . . 194 (2002) 105
Michaelian, K., see Cruz-Galindo, H.S. . . . 194 (2002) 319
Miller, T., see Javorsek II, D. . . . 194 (2002) 78
Millers, D., L. Grigorjeva, V. Pankratov, V.A. Trepakov and S.E. Kapphan, Pulsed electron beam excited transient absorption in $SrTiO_3$ . . . 194 (2002) 469

Mitaroff, A., see Agosteo, S. . . . 194 (2002) 399
Mittal, V.K., see Sharma, A. . . . 194 (2002) 7
Møller, S.P., see Andersen, H.H. . . . 194 (2002) 217
Moroz, F.V., see Portillo, M. . . . 194 (2002) 193
Mueller, A.C., see Roussière, B. . . . 194 (2002) 151
Murillo, G., see Romero, S. . . . 194 (2002) 164

Naddaf, M., S. Chakane, S. Jain, S.V. Bhoraskar and A.B. Mandale, Modification of sensing properties of metallophthalocyanine by an ECR plasma . . . 194 (2002) 54
Nageswara Rao, S.V.S., see Sharma, A. . . . 194 (2002) 7
Nair, K.G.M., see Santhakumar, K. . . . 194 (2002) 451
Nakayama, Y., see Kimura, Y. . . . 194 (2002) 187
Nathuram, R., see Singh, K. . . . 194 (2002) 1
Nie, D., see Li, X.-n. . . . 194 (2002) 47
Nikjoo, H., see Endo, S. . . . 194 (2002) 123
Nolen, J., see Portillo, M. . . . 194 (2002) 193
Novgorodov, A.F., see Dragoun, O. . . . 194 (2002) 112

Obert, J., see Roussière, B. . . . 194 (2002) 151
Obiajunwa, E.I., D.A. Pelemo, S.A. Owolabi, M.K. Fasasi and F.O. Johnson-Fatokun, Characterisation of heavy metal pollutants of soils and sediments around a crude-oil production terminal using EDXRF . . . 194 (2002) 61
Obiajunwa, E.I., F.O. Johnson-Fatokun, H.B. Olaniyi and A.F. Olowole, Determination of the elemental composition of aerosol samples in the working environment of a secondary lead smelting company in Nigeria using EDXRF technique . . . 194 (2002) 65
Olaniyi, H.B., see Obiajunwa, E.I. . . . 194 (2002) 65
Olowole, A.F., see Obiajunwa, E.I. . . . 194 (2002) 65
Orlov, S.Yu., see Portillo, M. . . . 194 (2002) 193
Otey, C.R., see Mastromarino, P.A. . . . 194 (2002) 69
Ottaviano, L., see Pakhomov, G.L. . . . 194 (2002) 269
Owolabi, S.A., see Obiajunwa, E.I. . . . 194 (2002) 61

Pakhomov, G.L., L.G. Pakhomov, V.I. Shashkin, J.M. Tura, J.M. Ribo and L. Ottaviano, Implantation and annealing effects in molecular organic films . . . 194 (2002) 269
Pakhomov, L.G., see Pakhomov, G.L. . . . 194 (2002) 269
Pankratov, V., see Millers, D. . . . 194 (2002) 469
Panteleev, V.N., see Portillo, M. . . . 194 (2002) 193
Pauwels, N., see Roussière, B. . . . 194 (2002) 151
Pelemo, D.A., see Obiajunwa, E.I. . . . 194 (2002) 61
Pimblott, S.M. and L.D.A. Siebbeles, Energy loss by non-relativistic electrons and positrons in liquid water . . . 194 (2002) 237
Portillo, M., J. Nolen, I. Gomes, V.N. Panteleev, D.V. Fedorov, A.E. Barzakh, V.I. Beznosjuk, F.V. Moroz, S.Yu. Orlov and Yu.M. Volkov, Production of neutron-rich isotopes by one- and two-step processes in ISOL targets . . . 194 (2002) 193
Potier, J.C., see Roussière, B. . . . 194 (2002) 151
Pougheon, F., see Roussière, B. . . . 194 (2002) 151
Pripstein, D., see Mastromarino, P.A. . . . 194 (2002) 69
Proust, J., see Roussière, B. . . . 194 (2002) 151
Puri, S., see Kumar, A. . . . 194 (2002) 99

Radivojevic, Z., A. Andrighetto, F. Brandolini, P. Dendooven, V. Lyapin, L. Stroe, L. Tecchio, W.H. Trzaska and D. Vakhtin, Neutron yields from a thick ^{13}C target irradiated by 30 MeV protons . . . 194 (2002) 251
Rau, E.I., see Jbara, O. . . . 194 (2002) 302
Ravichandran, V., see Santhakumar, K. . . . 194 (2002) 451
Reijme, M.A., M.P. de Jong, D.P.L. Simons, M. Schok, L.J. van IJzendoorn, A.W. Denier van der Gon, H.H. Brongersma and M.J.A. de Voigt, The distribution of $InCl_x$ compounds in model polymeric LED's: A combined low and high-energy ion beam analysis study . . . 194 (2002) 346
Ribo, J.M., see Pakhomov, G.L. . . . 194 (2002) 269

Rohrs, H., see Javorsek II, D. . . . 194 (2002) 78
Rolfs, C., see Baving, P. . . . 194 (2002) 363
Romero, S., M. Fernández, G. Murillo and H.M. Berdejo, Elastic forward analysis using ^{7}Li ions: A useful tool for H and light elements determination . . . 194 (2002) 164
Roussière, B., F. Ibrahim, J. Sauvage, O. Bajeat, N. Barré, F. Clapier, E. Cottereau, C. Donzaud, M. Ducourtieux, S. Essabaa, D. Guillemaud-Mueller, C. Lau, H. Lefort, C.F. Liang, F. Le Blanc, A.C. Mueller, J. Obert, N. Pauwels, J.C. Potier, F. Pougheon, J. Proust, O. Sorlin, D. Verney and A. Wojtasiewicz, Release properties of UC_x and molten U targets . . . 194 (2002) 151
Ryšavý, M., see Dragoun, O. . . . 194 (2002) 112

Sainkar, S.R., see Alegaonkar, P.S. . . . 194 (2002) 281
Salvetat, J.-P., see Costantini, J.-M. . . . 194 (2002) 132
Sánchez, H.J., Total reflection X-ray fluorescence analysis using plate beam-guides . . . 194 (2002) 90
Sannakki, B., see Sharma, A. . . . 194 (2002) 7
Santhakumar, K., P. Jayavel, R. Kesavamoorthy, P. Magudapathy, K.G.M. Nair and V. Ravichandran, Raman investigations on nitrogen ion implantation effects on semi-insulating InP . . . 194 (2002) 451
Sasase, M., see Ishigami, R. . . . 194 (2002) 257
Sata, N., see Matsunami, N. . . . 194 (2002) 443
Sauvage, J., see Roussière, B. . . . 194 (2002) 151
Schok, M., see Reijme, M.A. . . . 194 (2002) 346
Schut, H., see Holgado, J.P. . . . 194 (2002) 333
Sekiguchi, T., see Baba, Y. . . . 194 (2002) 41
Selen, L.J.M., A. van Loon, L.J. van IJzendoorn and M.J.A. de Voigt, Transmitted ion energy loss distributions to detect cluster formation in silicon . . . 194 (2002) 479
Shahi, J.S., see Kumar, A. . . . 194 (2002) 99
Shahi, J.S., see Kumar, A. . . . 194 (2002) 105
Shaikh, A.M., see Vaidya, S.J. . . . 194 (2002) 311
Shao, C.-l., see Shi, H.-b. . . . 194 (2002) 141
Shapiro, M.H. and T.A. Tombrello, Simulation of sputtering following ion bombardment at a target step . . . 194 (2002) 425
Sharma, A., P.K. Diwan, S. Kumar, S.K. Sharma, V.K. Mittal, S.V.S. Nageswara Rao, B. Sannakki, S. Ghosh and D.K. Avasthi, dE/dx measurements for heavy ions with $Z = 6$–29 in polycarbonate . . . 194 (2002) 7
Sharma, D.K., see Vaidya, S.J. . . . 194 (2002) 311
Sharma, S.K., see Sharma, A. . . . 194 (2002) 7
Sharma, V., see Singh, K. . . . 194 (2002) 1
Shashkin, V.I., see Pakhomov, G.L. . . . 194 (2002) 269
Shen, D.-Y., see Chen, F. . . . 194 (2002) 355
Shi, H.-b., C.-l. Shao and Z.-l. Yu, Studies on the mechanisms of the reactions between ethanol and D_2O by arc-discharge . . . 194 (2002) 141
Shibuya, K., M. Koshimizu, Y. Takeoka and K. Asai, Scintillation properties of $(C_6H_{13}NH_3)_2PbI_4$: Exciton luminescence of an organic/inorganic multiple quantum well structure compound induced by 2.0 MeV protons . . . 194 (2002) 207
Shimoyama, I., see Baba, Y. . . . 194 (2002) 41
Shimura, T., see Matsunami, N. . . . 194 (2002) 443
Shizuma, K., see Endo, S. . . . 194 (2002) 123
Siebbeles, L.D.A., see Pimblott, S.M. . . . 194 (2002) 237
Silari, M., see Agosteo, S. . . . 194 (2002) 399
Simons, D.P.L., see Reijme, M.A. . . . 194 (2002) 346
Singh, H., see Singh, K. . . . 194 (2002) 1
Singh, K., H. Singh, V. Sharma, R. Nathuram, A. Khanna, R. Kumar, S. Singh Bhatti and H. Singh Sahota, Gamma-ray attenuation coefficients in bismuth borate glasses . . . 194 (2002) 1
Singh, N., see Kumar, A. . . . 194 (2002) 99
Singh, N., see Kumar, A. . . . 194 (2002) 105
Singh Bhatti, S., see Singh, K. . . . 194 (2002) 1
Singh Sahota, S., see Singh, K. . . . 194 (2002) 1
Sorlin, O., see Roussière, B. . . . 194 (2002) 151
Špalek, A., see Dragoun, O. . . . 194 (2002) 112
Stohler, M., see Javorsek II, D. . . . 194 (2002) 78

Stroe, L., see Radivojevic, Z. 194 (2002) 251
Szűcs, Z., see Ido, T. 194 (2002) 369

Tai, H., see Wilson, J.W. 194 (2002) 389
Takeoka, Y., see Shibuya, K. 194 (2002) 207
Taratin, A., see Biino, C. 194 (2002) 417
Tárkányi, F., see Ido, T. 194 (2002) 369
Tassan-Got, L., A new functional for charge and mass identification in ΔE–E telescopes 194 (2002) 503
Tecchio, L., see Radivojevic, Z. 194 (2002) 251
Titov, A.I., V.S. Belyakov and S.O. Kucheyev, Molecular effect in semiconductors under heavy-ion bombardment: Quantitative approach based on the concept of nonlinear displacement spikes 194 (2002) 323
Tombrello, T.A., see Shapiro, M.H. 194 (2002) 425
Trepakov, V.A., see Millers, D. 194 (2002) 469
Tripathi, R.K., J.W. Wilson and F.A. Cucinotta, A method for calculating proton–nucleus elastic cross-sections 194 (2002) 229
Tripathi, R.K., see Wilson, J.W. 194 (2002) 389
Trzaska, W.H., see Radivojevic, Z. 194 (2002) 251
Tura, J.M., see Pakhomov, G.L. 194 (2002) 269
Tweed, J., see Wilson, J.W. 194 (2002) 389

Uehara, S., see Endo, S. 194 (2002) 123
Uggerhøj, U.I., see Andersen, H.H. 194 (2002) 217
Uggerhøj, U.I., see Biino, C. 194 (2002) 417
Ulrici, L., see Agosteo, S. 194 (2002) 399
Uzhinskii, V.V., see Biino, C. 194 (2002) 417

Vaidya, S.J., D.K. Sharma, A.M. Shaikh and A.N. Chandorkar, Neutron induced degradation in nitrided pyrogenic field oxide MOS capacitors 194 (2002) 311
Vakhtin, D., see Radivojevic, Z. 194 (2002) 251
van der Heide, P.A.W., Transient effects in SIMS analysis of Si with Cs^+ at high incidence angles: Secondary ion yield variations 194 (2002) 489
van IJzendoorn, L.J., see Selen, L.J.M. 194 (2002) 479
van Loon, A., see Selen, L.J.M. 194 (2002) 479
van Veen, A., see Holgado, J.P. 194 (2002) 333
Velasco, M., see Biino, C. 194 (2002) 417
Verney, D., see Roussière, B. 194 (2002) 151
Vogt, S., see Javorsek II, D. 194 (2002) 78
Volkov, Yu.M., see Portillo, M. 194 (2002) 193

Wang, D.-Y., see Chang, C.-L. 194 (2002) 463
Wang, K.-M., see Chen, F. 194 (2002) 355
Wang, X.-L., see Chen, F. 194 (2002) 355
Webb, R.P., see Barradas, N.P. 194 (2002) 15
Wendler, E., see Barradas, N.P. 194 (2002) 15
Wilson, J.W., see Tripathi, R.K. 194 (2002) 229
Wilson, J.W., J. Tweed, H. Tai and R.K. Tripathi, A simple model for straggling evaluation 194 (2002) 389
Woermann, D., Analysis of non-ohmic electrical current–voltage characteristic of membranes carrying a single track-etched conical pore 194 (2002) 458
Wojtasiewicz, A., see Roussière, B. 194 (2002) 151
Wu, S., see He, M. 194 (2002) 393

Xu, J.L., J.L. Chen and J.Y. Feng, Growth of Ge films by cluster beam deposition 194 (2002) 297

Yakushev, E.A., see Dragoun, O. 194 (2002) 112
Yasuda, K., see Ishigami, R. 194 (2002) 257

Yoshida, E., see Endo, S. 194 (2002) 123
Yu, Z.-l., see Shi, H.-b. 194 (2002) 141

Zabel, H., see Baving, P. 194 (2002) 363
Zecca, A., see Brusa, R.S. 194 (2002) 519
Zhang, S.L., see Chen, C.C. 194 (2002) 474
Zhu, D.Z., see Chen, C.C. 194 (2002) 474

Nuclear Instruments and Methods in Physics Research B 194 (2002) 543–545

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Beam Interactions with Materials & Atoms

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Subject index

Basic Data for Materials Modifications and Analysis

Gamma-ray attenuation coefficients in bismuth borate glasses, K. Singh, H. Singh, V. Sharma, R. Nathuram, A. Khanna, R. Kumar, S. Singh Bhatti and H. Singh Sahota 194 (2002) 1
dE/dx measurements for heavy ions with $Z = 6$–29 in polycarbonate, A. Sharma, P.K. Diwan, S. Kumar, S.K. Sharma, V.K. Mittal, S.V.S. Nageswara Rao, B. Sannakki, S. Ghosh and D.K. Avasthi 194 (2002) 7
Accurate determination of the stopping power of ^{4}He in Si using Bayesian inference, N.P. Barradas, C. Jeynes, R.P. Webb and E. Wendler 194 (2002) 15
Differential cross-section measurements for inelastic scattering of 22.1 keV photons by elements with $4 \leqslant Z \leqslant 69$, A. Kumar, J.S. Shahi, S. Puri, D. Mehta and N. Singh 194 (2002) 99
Differential cross-section measurements for elastic scattering of 22.1 keV photons by elements with $6 \leqslant Z \leqslant 81$, A. Kumar, J.S. Shahi, D. Mehta and N. Singh 194 (2002) 105
An apparatus to measure stopping powers for low-energy antiprotons and protons, H.H. Andersen, A. Csete, T. Ichioka, H. Knudsen, S.P. Møller and U.I. Uggerhøj 194 (2002) 217
Monte Carlo simulations of neutron fluxes for varying rock types, J.A. Dunne 194 (2002) 226
A method for calculating proton–nucleus elastic cross-sections, R.K. Tripathi, J.W. Wilson and F.A. Cucinotta 194 (2002) 229
Energy loss by non-relativistic electrons and positrons in liquid water, S.M. Pimblott and L.D.A. Siebbeles . . 194 (2002) 237
Neutron yields from a thick ^{13}C target irradiated by 30 MeV protons, Z. Radivojevic, A. Andrighetto, F. Brandolini, P. Dendooven, V. Lyapin, L. Stroe, L. Tecchio, W.H. Trzaska and D. Vakhtin 194 (2002) 251
Stopping power of He ions in niobium from a comparison of RBS and X-ray reflectivity measurements, P. Baving, H.W. Becker, C. Rolfs and H. Zabel 194 (2002) 363
Excitation functions of proton induced nuclear reactions on ^{nat}Rb from 30 to 70 MeV. Implication for the production of ^{82}Sr and other medically important Rb and Sr radioisotopes, T. Ido, A. Hermanne, F. Ditrói, Z. Szűcs, I. Mahunka and F. Tárkányi. 194 (2002) 369
A simple model for straggling evaluation, J.W. Wilson, J. Tweed, H. Tai and R.K. Tripathi. 194 (2002) 389
Measurement of the half-life of ^{79}Se with PX-AMS, M. He, S. Jiang, S. Jiang, L. Diao, S. Wu and C. Li 194 (2002) 393
Neutron production from 158 GeV/c per nucleon lead ions on thin copper and lead targets in the angular range 30–135°, S. Agosteo, C. Birattari, A. Foglio Para, L. Gini, A. Mitaroff, M. Silari and L. Ulrici 194 (2002) 399

Atomic Collisions in Solids

Classical dynamics simulations of directional effects in sputtering from a bimetallic surface: c(2 × 2)-Pb/Cu(100), M.A. Karolewski 194 (2002) 26
Scattering of 7.3 keV conversion electrons from a ^{57}Co source covered gradually by gold absorbers of various thicknesses, O. Dragoun, A. Špalek, A. Kovalík, E.A. Yakushev, M. Ryšavý, J. Frána, V. Brabec, A.F. Novgorodov and D. Liljequist. 194 (2002) 112
Transmission ERDA measurement of deuterium in titanium with thickness ~70 μm using 15 MeV ^{4}He beams, R. Ishigami, Y. Ito, K. Yasuda, M. Sasase and S. Hatori 194 (2002) 257
Sputtering of copper atoms by keV atomic and molecular ions: A comparison of experiment with analytical and computer based models, D.R. Gillen, W.G. Graham and A. Goelich 194 (2002) 409
On the reduced interaction probability for fully stripped 33 TeV/c Pb ions channeled in a bent Si crystal, C. Biino, M. Clément, N. Doble, K. Elsener, A. Freund, L. Gatignon, P. Grafström, W. Herr, A. Taratin, U.I. Uggerhøj, V.V. Uzhinskii and M. Velasco 194 (2002) 417
Simulation of sputtering following ion bombardment at a target step, M.H. Shapiro and T.A. Tombrello 194 (2002) 425
Electron stimulated molecular desorption of a non-evaporable Zr–V–Fe alloy getter at room temperature, F. Le Pimpec, O. Gröbner and J.M. Laurent. 194 (2002) 434

PII: S0168-583X(02)01449-0

Ion Beam Modification of Materials

Local electronic and geometric structures of silicon atoms implanted in graphite, Y. Baba, T. Sekiguchi and I. Shimoyama. . . . 194 (2002) 41
A comparative study on microstructures of β-$FeSi_2$ and carbon-doped β-$Fe(Si,C)_2$ films by transmission electron microscopy, X.-n. Li, D. Nie and C. Dong . . . 194 (2002) 47
Modification of sensing properties of metallophthalocyanine by an ECR plasma, M. Naddaf, S. Chakane, S. Jain, S.V. Bhoraskar and A.B. Mandale . . . 194 (2002) 54
Implantation and annealing effects in molecular organic films, G.L. Pakhomov, L.G. Pakhomov, V.I. Shashkin, J.M. Tura, J.M. Ribo and L. Ottaviano . . . 194 (2002) 269
Refractive index and dielectric constant of the boron and fluorine diffused polyimide, P.S. Alegaonkar, A.B. Mandale, S.R. Sainkar and V.N. Bhoraskar . . . 194 (2002) 281
Reduction of the tensile stress in $CoSi_2$ films by pre-deposition carbon ion implantation, J.F. Liu, J.Y. Feng and W.Z. Li . . . 194 (2002) 289
Growth of Ge films by cluster beam deposition, J.L. Xu, J.L. Chen and J.Y. Feng . . . 194 (2002) 297
Ion irradiation effects on $SrCeO_3$ thin films, N. Matsunami, T. Shimura, H. Iwahara, N. Sata and M. Ishigame 194 (2002) 443
Raman investigations on nitrogen ion implantation effects on semi-insulating InP, K. Santhakumar, P. Jayavel, R. Kesavamoorthy, P. Magudapathy, K.G.M. Nair and V. Ravichandran. . . . 194 (2002) 451
Analysis of non-ohmic electrical current–voltage characteristic of membranes carrying a single track-etched conical pore, D. Woermann. . . . 194 (2002) 458
Characterization of surface enhancement of carbon ion-implanted TiN coatings by metal vapor vacuum arc ion implantation, C.-L. Chang and D.-Y. Wang . . . 194 (2002) 463

Effects of Radiation

A Monte Carlo track structure code for low energy protons, S. Endo, E. Yoshida, H. Nikjoo, S. Uehara, M. Hoshi, M. Ishikawa and K. Shizuma . . . 194 (2002) 123
Micro-Raman study of the carbonization of polyimide induced by swift heavy ion irradiations, J.-M. Costantini, F. Couvreur, J.-P. Salvetat and S. Bouffard . . . 194 (2002) 132
Studies on the mechanisms of the reactions between ethanol and D_2O by arc-discharge, H.-b. Shi, C.-l. Shao and Z.-l. Yu . . . 194 (2002) 141
Release properties of UC_x and molten U targets, B. Roussière, F. Ibrahim, J. Sauvage, O. Bajeat, N. Barré, F. Clapier, E. Cottereau, C. Donzaud, M. Ducourtieux, S. Essabaa, D. Guillemaud-Mueller, C. Lau, H. Lefort, C.F. Liang, F. Le Blanc, A.C. Mueller, J. Obert, N. Pauwels, J.C. Potier, F. Pougheon, J. Proust, O. Sorlin, D. Verney and A. Wojtasiewicz. . . . 194 (2002) 151
A new experimental approach for characterizing the internal trapped charge and electric field build up in ground-coated insulators during their e^- irradiation, O. Jbara, S. Fakhfakh, M. Belhaj, J. Cazaux, E.I. Rau, M. Filippov and M.V. Andrianov . . . 194 (2002) 302
Neutron induced degradation in nitrided pyrogenic field oxide MOS capacitors, S.J. Vaidya, D.K. Sharma, A.M. Shaikh and A.N. Chandorkar . . . 194 (2002) 311
Luminescence model with quantum impact parameter for low energy ions, H.S. Cruz-Galindo, K. Michaelian, A. Martínez-Dávalos, E. Belmont-Moreno and S. Galindo. . . . 194 (2002) 319
Molecular effect in semiconductors under heavy-ion bombardment: Quantitative approach based on the concept of nonlinear displacement spikes, A.I. Titov, V.S. Belyakov and S.O. Kucheyev. . . . 194 (2002) 323
Pulsed electron beam excited transient absorption in $SrTiO_3$, D. Millers, L. Grigorjeva, V. Pankratov, V.A. Trepakov and S.E. Kapphan . . . 194 (2002) 469

Analysis of Materials

Characterisation of heavy metal pollutants of soils and sediments around a crude-oil production terminal using EDXRF, E.I. Obiajunwa, D.A. Pelemo, S.A. Owolabi, M.K. Fasasi and F.O. Johnson-Fatokun. . . . 194 (2002) 61
Determination of the elemental composition of aerosol samples in the working environment of a secondary lead smelting company in Nigeria using EDXRF technique, E.I. Obiajunwa, F.O. Johnson-Fatokun, H.B. Olaniyi and A.F. Olowole. . . . 194 (2002) 65
Tunable diode laser study of pressure broadening of Rb D_1 lines in the presence of ^4He buffer gas, P.A. Mastromarino, C.R. Otey, D. Pripstein and E.W. Hughes . . . 194 (2002) 69

Testing the atomic structure of beryllium with AMS, D. Javorsek II, D. Elmore, E. Fischbach, T. Miller, M. Stohler, M. Bourgeois, D. Hillegonds, J. Marder, H. Rohrs and S. Vogt 194 (2002) 78
Elastic forward analysis using ^{7}Li ions: A useful tool for H and light elements determination, S. Romero, M. Fernández, G. Murillo and H.M. Berdejo 194 (2002) 164
Difference between bulk and thin film densities of metal oxide and fluoride films studied by NRA depth profiling techniques, A. Coban, E.E. Khawaja and S.M.A. Durrani 194 (2002) 171
Ion beam analysis of rough thin films, M. Mayer 194 (2002) 177
Irradiation effect of synchrotron radiation on crystallization of thin amorphous WO_3 film, Y. Kimura, K. Hanamoto, Y. Nakayama and C. Kaito 194 (2002) 187
Structural effects due to the incorporation of Ar atoms in the lattice of ZrO_2 thin films prepared by ion beam assisted deposition, J.P. Holgado, R.E. Galindo, A. van Veen, H. Schut, J.Th.M. de Hosson and A.R. González-Elipe 194 (2002) 333
The distribution of $InCl_x$ compounds in model polymeric LED's: A combined low and high-energy ion beam analysis study, M.A. Reijme, M.P. de Jong, D.P.L. Simons, M. Schok, L.J. van IJzendoorn, A.W. Denier van der Gon, H.H. Brongersma and M.J.A. de Voigt 194 (2002) 346
Retardation of strain relaxation in Si/SiGe/Si heterostructures during high temperature oxidation, C.C. Chen, A.-C. Lindgren, S.L. Zhang and D.Z. Zhu 194 (2002) 474
Transmitted ion energy loss distributions to detect cluster formation in silicon, L.J.M. Selen, A. van Loon, L.J. van IJzendoorn and M.J.A. de Voigt 194 (2002) 479
Transient effects in SIMS analysis of Si with Cs^{+} at high incidence angles: Secondary ion yield variations, P.A.W. van der Heide 194 (2002) 489

Ion Sources and Beam Optics

Production of neutron-rich isotopes by one- and two-step processes in ISOL targets, M. Portillo, J. Nolen, I. Gomes, V.N. Panteleev, D.V. Fedorov, A.E. Barzakh, V.I. Beznosjuk, F.V. Moroz, S.Yu. Orlov and Yu.M. Volkov 194 (2002) 193

Experimental Methods and Equipment

Total reflection X-ray fluorescence analysis using plate beam-guides, H.J. Sánchez 194 (2002) 90
Scintillation properties of $(C_6H_{13}NH_3)_2PbI_4$: Exciton luminescence of an organic/inorganic multiple quantum well structure compound induced by 2.0 MeV protons, K. Shibuya, M. Koshimizu, Y. Takeoka and K. Asai 194 (2002) 207
A new functional for charge and mass identification in ΔE–E telescopes, L. Tassan-Got 194 (2002) 503
On the efficiency calibration of Si(Li) detector in the low-energy region using thick-target bremsstrahlung, Z. An and M.T. Liu 194 (2002) 513
Doppler-broadening measurements of positron annihilation with high-momentum electrons in pure elements, R.S. Brusa, W. Deng, G.P. Karwasz and A. Zecca 194 (2002) 519

Letters to the Editor

Property study on nickel ion implanted planar waveguide in $KTiOAsO_4$ crystal, F. Chen, X.-L. Wang, Q.-M.Lu, G. Fu, S.-L. Li, F. Lu, K.-M. Wang and D.-Y. Shen 194 (2002) 355